Se	earch N	otes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/014,428	OHTA, SEIYA
Examiner	Art Unit
Chriss S. Yoder, III	2622

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Class	Subclass	Date	Examiner
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INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
East Search Updated	10/4/2006	CY
Spoke with Greg Madden	10/4/2006	CY
Spoke with Yogesh Aggarwal	10/4/2006	CY